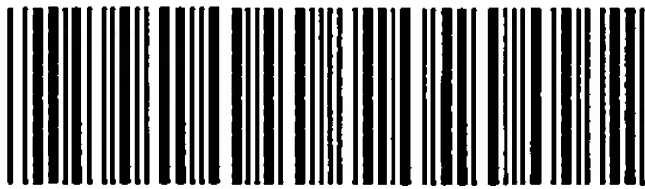


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/657,259	SHIRAISHI ET AL.	
	Examiner	Art Unit	
	Christopher S. Kim	3752	

SEARCHED			
Class	Subclass	Date	Examiner
239	533.12	7/7/2005	CK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR